

TOSHIBA Transistor Silicon NPN Triple Diffused Type (Darlington)

# 2SD2131

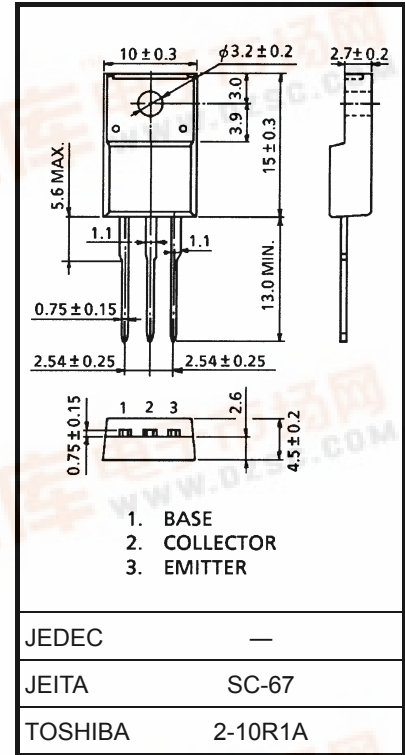
High-Power Switching Applications  
Hammer Drive, Pulse Motor Drive Applications

Unit: mm

- High DC current gain:  $h_{FE} = 2000$  (min) ( $V_{CE} = 3\text{ V}$ ,  $I_C = 3\text{ A}$ )
- Low saturation voltage:  $V_{CE(sat)} = 1.5\text{ V}$  (max) ( $I_C = 3\text{ A}$ )
- Zener diode included between collector and base.
- Unclamped inductive load energy:  $E = 150\text{ mJ}$  (min)

## Absolute Maximum Ratings ( $T_c = 25^\circ\text{C}$ )

Characteristics		Symbol	Rating	Unit
Collector-base voltage		$V_{CBO}$	$60 \pm 10$	V
Collector-emitter voltage		$V_{CEO}$	$60 \pm 10$	V
Emitter-base voltage		$V_{EBO}$	7	V
Collector current	DC	$I_C$	5	A
	Pulse	$I_{CP}$	8	
Base current		$I_B$	0.5	A
Collector power dissipation	$T_a = 25^\circ\text{C}$	$P_C$	2.0	W
	$T_c = 25^\circ\text{C}$		30	
Junction temperature		$T_j$	150	$^\circ\text{C}$
Storage temperature range		$T_{stg}$	-55 to 150	$^\circ\text{C}$

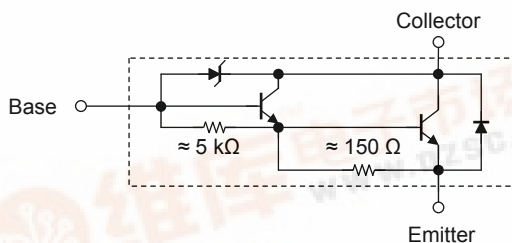


Weight: 1.7 g (typ.)

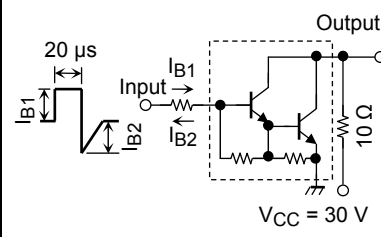
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

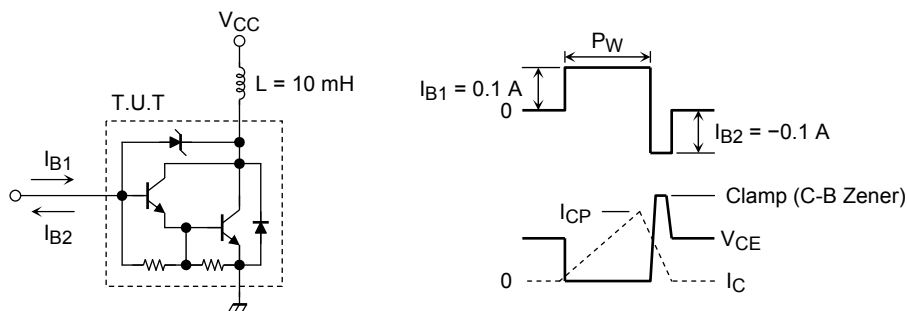
## Equivalent Circuit



## Electrical Characteristics (Tc = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		$I_{CBO}$	$V_{CB} = 45\text{ V}, I_E = 0$	—	—	10	$\mu\text{A}$
Collector cut-off current		$I_{CEO}$	$V_{CE} = 45\text{ V}, I_B = 0$	—	—	10	$\mu\text{A}$
Emitter cut-off current		$I_{EBO}$	$V_{EB} = 6\text{ V}, I_C = 0$	—	—	2.5	$\text{mA}$
Collector-base breakdown voltage		$V_{(BR)CBO}$	$I_C = 1\text{ mA}, I_E = 0$	50	60	70	$\text{V}$
Collector-emitter breakdown voltage		$V_{(BR)CEO}$	$I_C = 10\text{ mA}, I_B = 0$	50	60	70	$\text{V}$
DC current gain		$h_{FE(1)}$	$V_{CE} = 3\text{ V}, I_C = 3\text{ A}$	2000	—	15000	
		$h_{FE(2)}$	$V_{CE} = 3\text{ V}, I_C = 5\text{ A}$	1000	—	—	
Collector-emitter saturation voltage		$V_{CE(sat)(1)}$	$I_C = 3\text{ A}, I_B = 6\text{ mA}$	—	1.1	1.5	$\text{V}$
		$V_{CE(sat)(2)}$	$I_C = 5\text{ A}, I_B = 20\text{ mA}$	—	1.3	2.5	
Base-emitter saturation voltage		$V_{BE(sat)}$	$I_C = 3\text{ A}, I_B = 6\text{ mA}$	—	1.7	2.5	$\text{V}$
Unclamped inductive load energy		$E_{S/B}$	(Note 1)	150	—	—	$\text{mJ}$
Switching time	Turn-on time	$t_{on}$		—	1.0	—	$\mu\text{s}$
	Storage time	$t_{stg}$		—	4.0	—	
	Fall time	$t_f$		—	2.5	—	

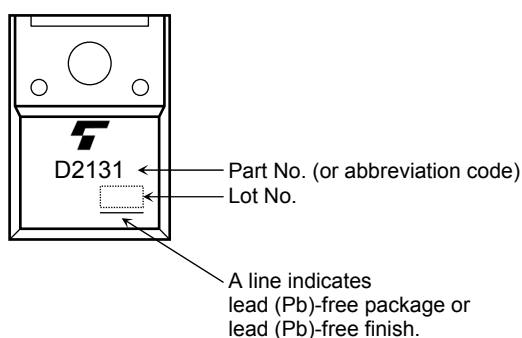
Note 1: Measurement circuit for unclamped inductive load energy

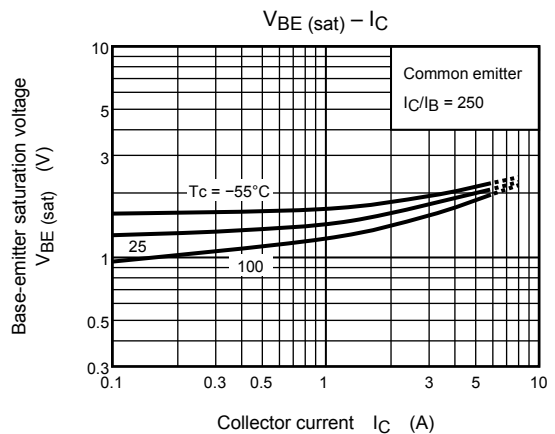
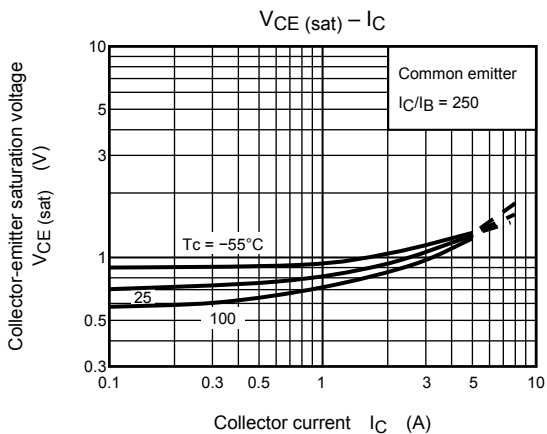
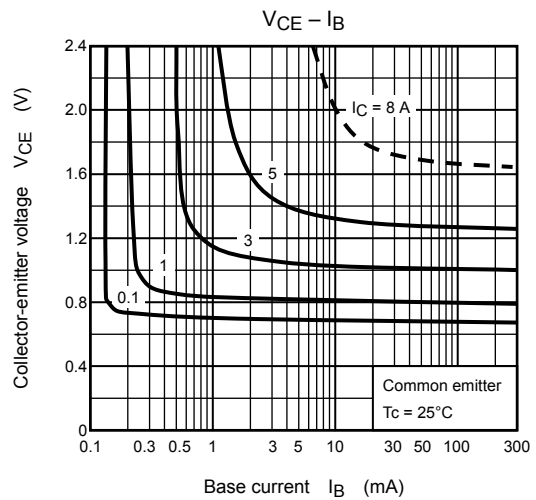
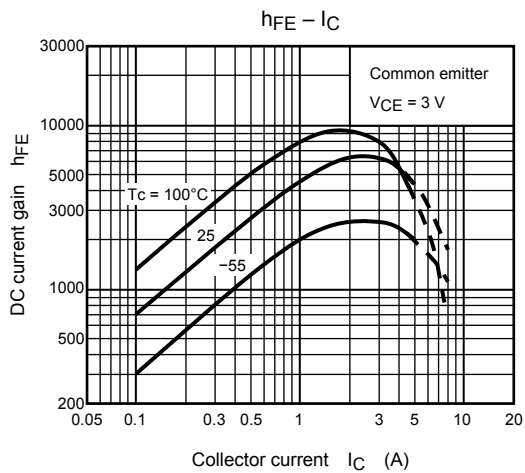
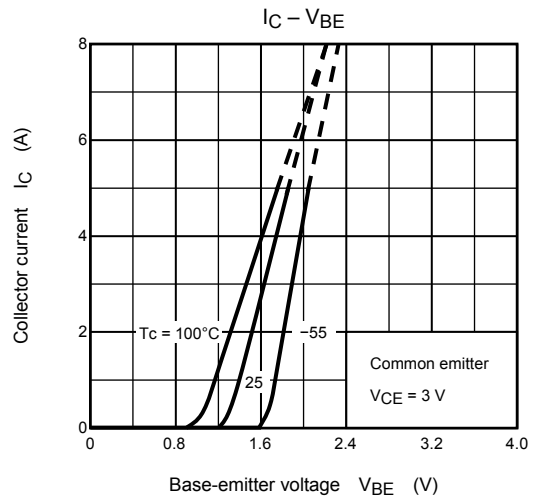
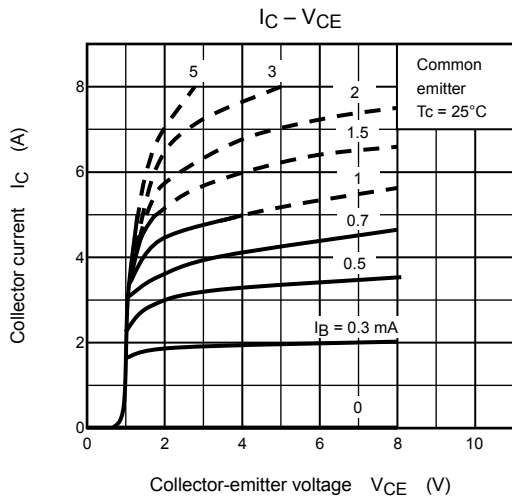


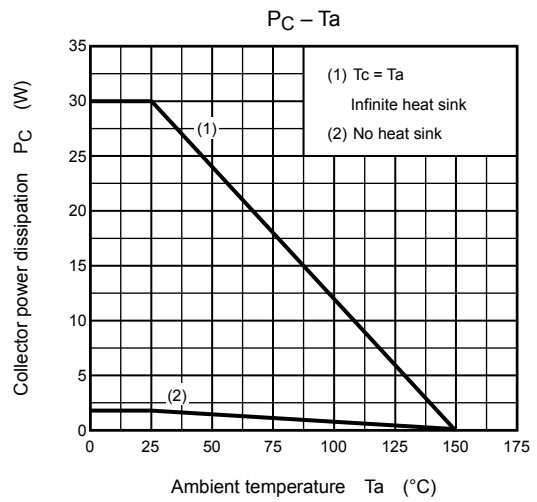
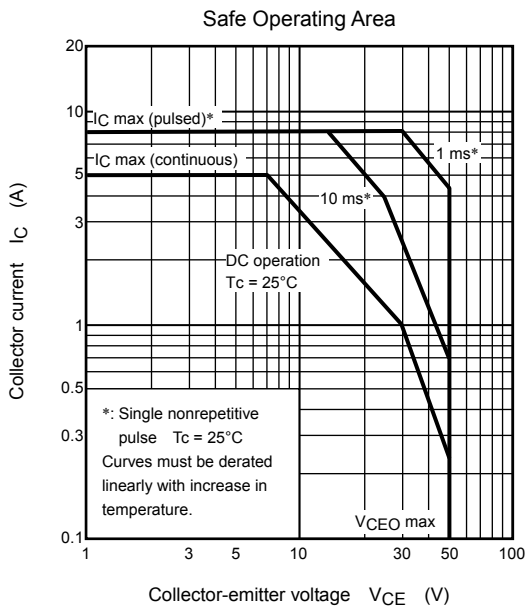
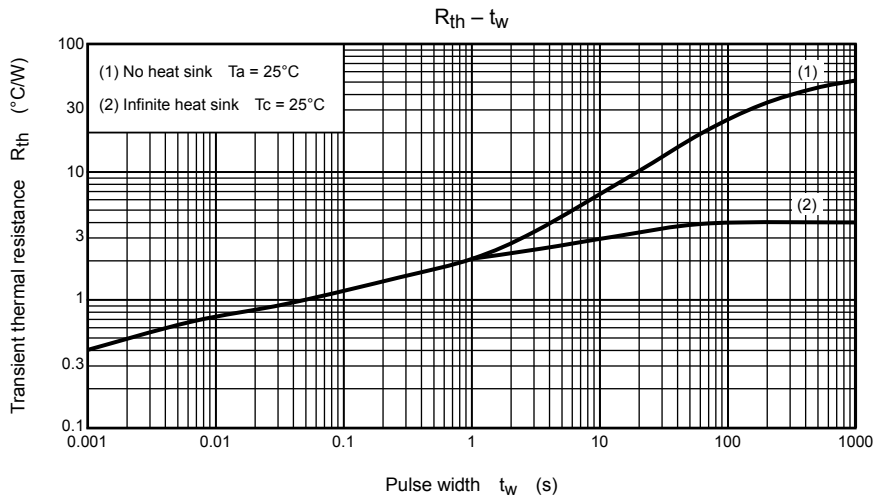
Note 2: (1) Pulse width adjusted for desired  $I_{CP}$  ( $I_{CP} = 5.47\text{ A min}$ )

$$(2) E = 1/2 L I_{CP}^2$$

## Marking







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20070701-EN

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